

**Search Notes**

Application/Control No.

10/519,672

Examiner

David E. Bochna

Applicant(s)/Patent under  
Reexamination

MATSUHASHI ET AL.

Art Unit

3679

**SEARCHED**

Class	Subclass	Date	Examiner
285	255	10/13/2006	DB
	332.1		
	249		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR